

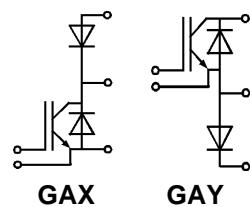
Absolute Maximum Ratings		Values		Units
Symbol	Conditions <sup>1)</sup>			
$V_{CES}$		1200		V
$V_{CGR}$	$R_{GE} = 20 \text{ k}\Omega$	1200		V
$I_C$	$T_{case} = 25/80^\circ\text{C}$	145 / 110		A
$I_{CM}$	$T_{case} = 25/80^\circ\text{C}; t_p = 1 \text{ ms}$	290 / 220		A
$V_{GES}$		$\pm 20$		V
$P_{tot}$	per IGBT, $T_{case} = 25^\circ\text{C}$	830		W
$T_j, (T_{stg})$		-40 ... +150 (125)		°C
$V_{isol}$	AC, 1 min.	2500		V
humidity	DIN 40 040	Class F		
climate	DIN IEC 68 T.1	40/125/56		
Diode		Inverse	Series <sup>6)</sup>	
$I_F = -I_C$	$T_{case} = 25/80^\circ\text{C}$	130 / 90	145 / 115	A
$I_{FM} = -I_{CM}$	$T_{case} = 25/80^\circ\text{C}; t_p = 1 \text{ ms}$	300 / 220	290 / 220	A
$I_{FSM}$	$t_p = 10 \text{ ms}; \sin.; T_j = 150^\circ\text{C}$	1100	1450	A
$I^{2t}$	$t_p = 10 \text{ ms}; T_j = 150^\circ\text{C}$	6000	10500	A <sup>2</sup> s

## SEMITRANS® M IGBT Modules

SKM 145 GAX 123 D <sup>6)</sup>  
SKM 145 GAY 123 D <sup>6)</sup>



## SEMITRANS 2



Characteristics				
Symbol	Conditions <sup>1)</sup>	min.	typ.	max.
$V_{(BR)CES}$	$V_{GE} = 0, I_C = 4 \text{ mA}$	$\geq V_{CES}$	-	-
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 4 \text{ mA}$	4,5	5,5	6,5
$I_{CES}$	$V_{GE} = 0$	-	0,2	2
	$T_j = 25^\circ\text{C}$			mA
	$V_{CE} = V_{CES}$	-	9	-
	$T_j = 125^\circ\text{C}$			mA
$I_{GES}$	$V_{GE} = 20 \text{ V}, V_{CE} = 0$	-	-	1
$\mu\text{A}$				
$V_{CEsat}$	$I_C = 100 \text{ A}$	2,5(3,1)	3(3,7)	V
$V_{CEsat}$	$\left. \begin{array}{l} V_{GE} = 15 \text{ V}; \\ I_C = 150 \text{ A} \end{array} \right\} T_j = 25 \text{ (125)}^\circ\text{C}$	3(3,8)	-	V
$g_{fs}$	$V_{CE} = 20 \text{ V}, I_C = 100 \text{ A}$	54	-	S
$C_{CHC}$	per IGBT	-	-	350
$C_{ies}$	$\left. \begin{array}{l} V_{GE} = 0 \\ V_{CE} = 25 \text{ V} \end{array} \right\} f = 1 \text{ MHz}$	-	6,5	8,5
$C_{oes}$		-	1000	1500
$C_{res}$		-	500	600
$L_{CE}$		-	-	30
$n\text{H}$				
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$	-	160	320
$t_r$	$V_{GE} = +15 \text{ V} / -15 \text{ V}^3)$	-	80	160
$t_{d(off)}$	$I_C = 100 \text{ A}, \text{ind. load}$	-	400	520
$t_f$	$R_{Gon} = R_{Goff} = 6,8 \Omega$	-	70	100
$E_{on}^5)$	$T_j = 125^\circ\text{C}$	-	16	-
$E_{off}^5)$		-	12	-
				mWs
				mWs
Inverse Diode <sup>8)</sup>				
$V_F = V_{EC}$	$I_F = 100 \text{ A}$	2,0(1,8)	2,5	V
$V_F = V_{EC}$	$\left. \begin{array}{l} I_F = 150 \text{ A} \\ T_j = 25 \text{ (125)}^\circ\text{C} \end{array} \right\}$	2,25(2,1)	-	V
$V_{TO}$	$T_j = 125^\circ\text{C}$	-	-	1,2
$r_T$	$T_j = 125^\circ\text{C}$	-	8	$\text{m}\Omega$
$I_{RRM}$	$I_F = 100 \text{ A}; T_j = 25 \text{ (125)}^\circ\text{C}^2)$	35(50)	-	A
$Q_{rr}$	$I_F = 100 \text{ A}; T_j = 25 \text{ (125)}^\circ\text{C}^2)$	5(14)	-	$\mu\text{C}$
Series Diode <sup>6) 8)</sup>				
$V_F = V_{EC}$	$I_F = 100 \text{ A}$	1,9(1,7)	2,4	V
$V_F = V_{EC}$	$\left. \begin{array}{l} I_F = 150 \text{ A} \\ T_j = 25 \text{ (125)}^\circ\text{C} \end{array} \right\}$	2,1(1,8)	-	V
$V_{TO}$	$T_j = 125^\circ\text{C}$	-	-	1,2
$r_T$	$T_j = 125^\circ\text{C}$	-	-	$\text{m}\Omega$
$I_{RRM}$	$I_F = 100 \text{ A}; T_j = 25 \text{ (125)}^\circ\text{C}^2)$	40(65)	-	A
$Q_{rr}$	$I_F = 100 \text{ A}; T_j = 25 \text{ (125)}^\circ\text{C}^2)$	5(15)	-	$\mu\text{C}$
Thermal characteristics				
$R_{thjc}$	per IGBT	-	-	0,15
$R_{thjc}$	per inverse/series diode <sup>6)</sup>	-	-	$^{\circ}\text{C}/\text{W}$
$R_{thch}$	per module	-	-	0,36/0,30
		-	-	$^{\circ}\text{C}/\text{W}$
		-	-	0,05
				$^{\circ}\text{C}/\text{W}$

## Features

- N channel, Homogeneous Silicon structure (NPT-IGBT)
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to  $6 * I_{cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes <sup>8)</sup>
- Isolated copper baseplate using DCB Direct Copper Bonding
- Large clearance (10 mm) and creepage distances (20 mm).

## Typical Applications

- Switching (not for linear use)
- Bidirectional switches
- Regenerative Braking
- Quasi resonant inverters (CSI)

<sup>1)</sup>  $T_{case} = 25^\circ\text{C}$ , unless otherwise specified

<sup>2)</sup>  $I_F = -I_C, V_R = 600 \text{ V}, -di_F/dt = 1000 \text{ A}/\mu\text{s}, V_{GE} = 0 \text{ V}$

<sup>3)</sup> Use  $V_{GEoff} = -5 \dots -15 \text{ V}$

<sup>5)</sup> See fig. 2 + 3;  $R_{Goff} = 6,8 \Omega$

<sup>6)</sup> The series diodes have the data of the inverse diodes of SKM 200 GB 123 D

<sup>8)</sup> CAL = Controlled Axial Lifetime Technology.

## Cases and mech. data

→ B 6 – 130

Diagrams of IGBT and inverse diode → B 6 – 124, of series diode on B 6 – 152 to 153

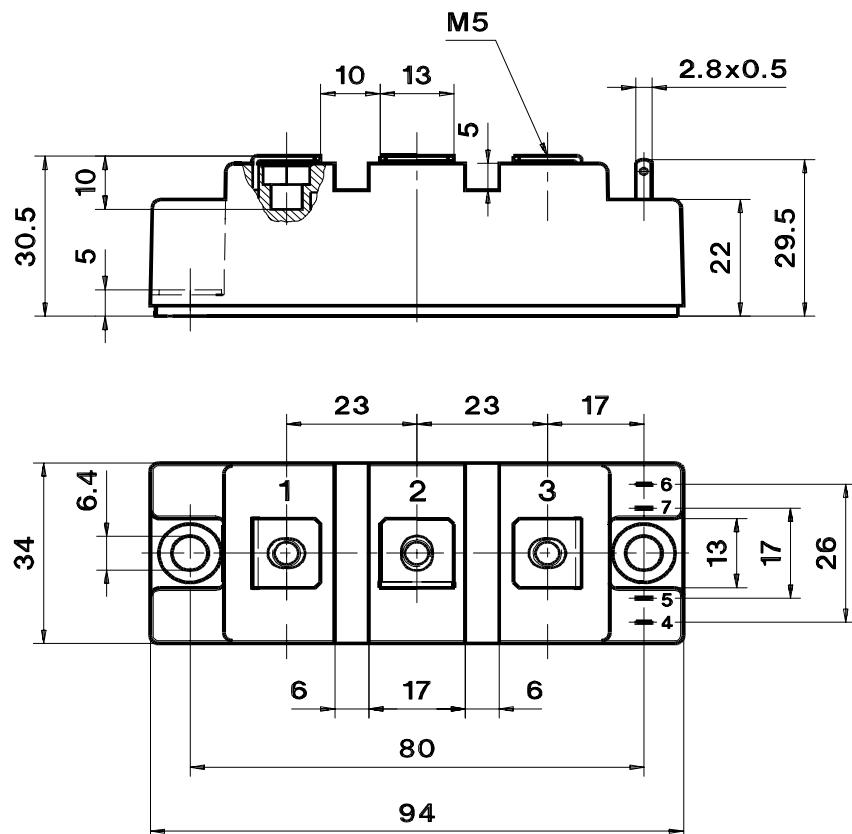
# SKM 145 GAX(Y) 123 D

## SEMITRANS 2

Case D 61  
UL Recognized  
File no. E 63 532

CASED61

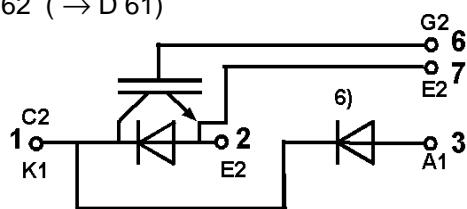
## SKM 145 GB 123 D



Dimensions in mm

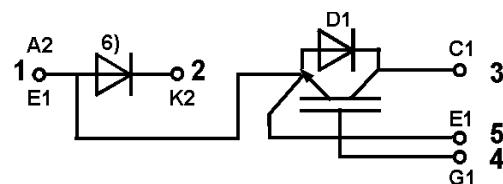
## SKM 145 GAX 123 D

Case D 62 (→ D 61)



## SKM 145 GAY 123 D

Case D 63 (→ D 61)



Case outline and circuit diagrams

## Mechanical Data

Symbol	Conditions		Values		Units	
			min.	typ.	max.	
M <sub>1</sub>	to heatsink, SI Units	(M6)	3	—	5	Nm
	to heatsink, US Units		27	—	44	lb.in.
M <sub>2</sub>	for terminals, SI Units	(M5)	2,5	—	5	Nm
	for terminals, US Units		22	—	44	lb.in.
a <sub>w</sub>			—	—	5x9,81	m/s <sup>2</sup>
			—	—	160	g

<sup>6)</sup> Series diode → B 6 – 129, remark 6.

This is an electrostatic discharge sensitive device (ESDS).

Please observe the international standard IEC 747-1, Chapter IX.

Three devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 3). Larger packing units of 12 and 20 pieces are used if suitable Accessories → B 6 – 4. SEMIBOX → C – 1.

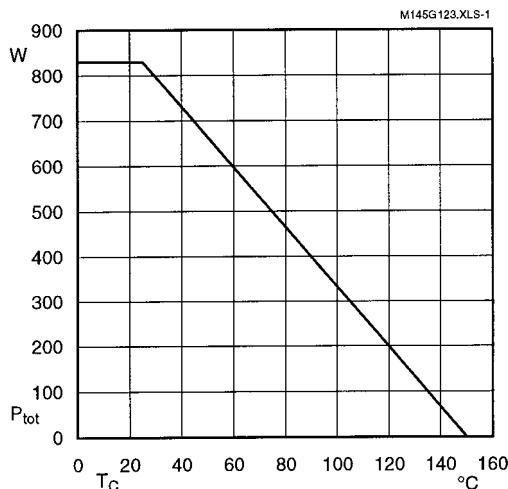


Fig. 1 Rated power dissipation  $P_{tot} = f(T_C)$

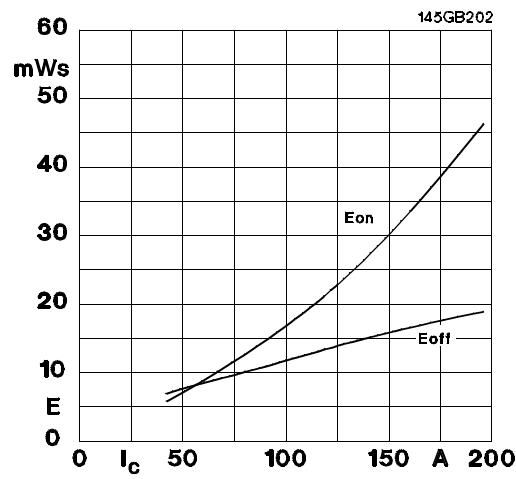


Fig. 2 Turn-on /-off energy  $= f(I_C)$

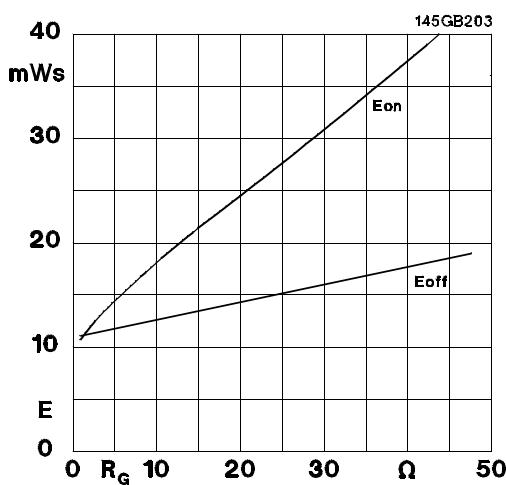


Fig. 3 Turn-on /-off energy  $= f(R_G)$

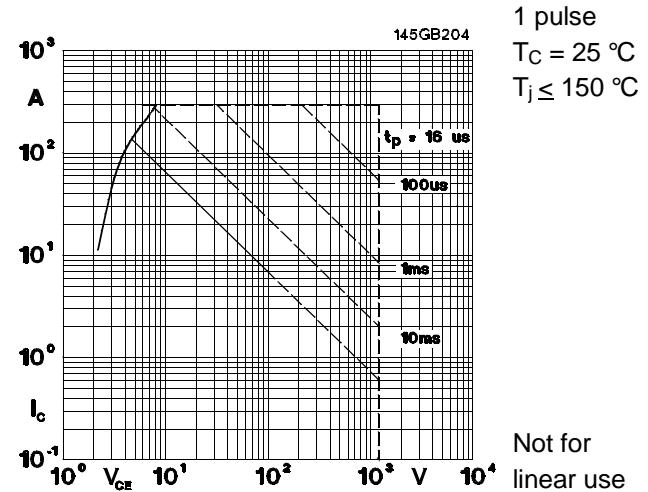


Fig. 4 Maximum safe operating area (SOA)  $I_C = f(V_{CE})$

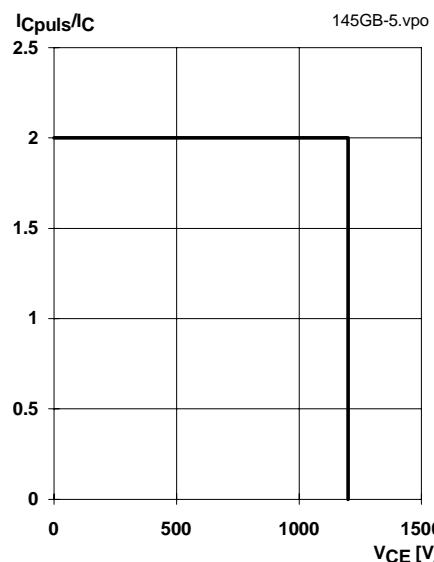


Fig. 5 Turn-off safe operating area (RBSOA)

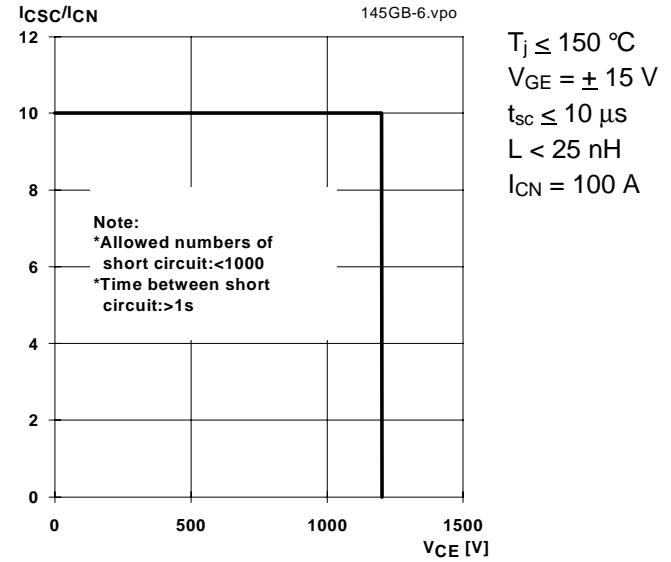
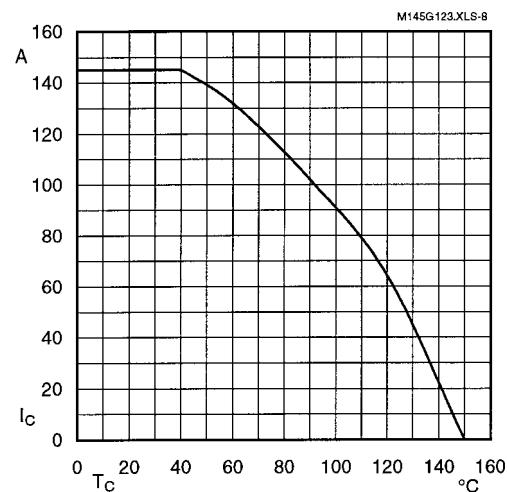


Fig. 6 Safe operating area at short circuit  $I_C = f(V_{CE})$



$T_j = 150 \text{ }^\circ\text{C}$   
 $V_{GE} \geq 15 \text{ V}$

Fig. 8 Rated current vs. temperature  $I_c = f(T_c)$

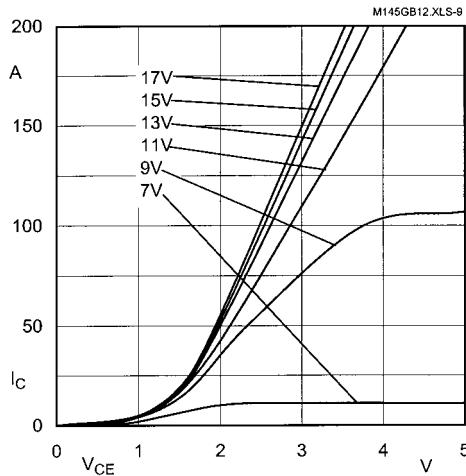


Fig. 9 Typ. output characteristic,  $t_p = 80 \mu\text{s}$ ;  $25 \text{ }^\circ\text{C}$

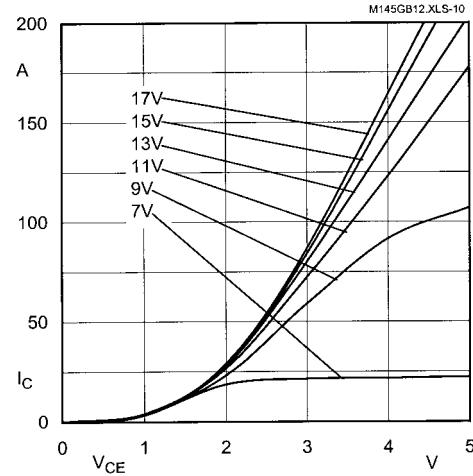


Fig. 10 Typ. output characteristic,  $t_p = 80 \mu\text{s}$ ;  $125 \text{ }^\circ\text{C}$

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_C(t)$$

$$V_{CEsat(t)} = V_{CE(TO)(Tj)} + r_{CE(Tj)} \cdot I_C(t)$$

$$V_{CE(TO)(Tj)} \leq 1,5 + 0,002 (T_j - 25) [\text{V}]$$

$$\text{typ.: } r_{CE(Tj)} = 0,010 + 0,00004 (T_j - 25) [\Omega]$$

$$\text{max.: } r_{CE(Tj)} = 0,015 + 0,00005 (T_j - 25) [\Omega]$$

valid for  $V_{GE} = + 15 \begin{matrix} +2 \\ -1 \end{matrix} \text{ [V]}$ ;  $I_C > 0,3 I_{Cnom}$

Fig. 11 Saturation characteristic (IGBT)  
 Calculation elements and equations

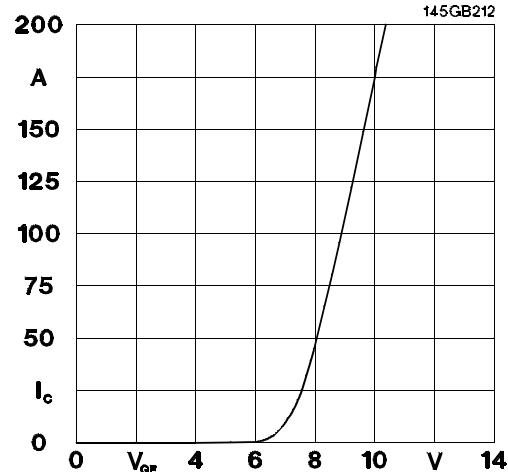


Fig. 12 Typ. transfer characteristic,  $t_p = 80 \mu\text{s}$ ;  $V_{CE} = 20 \text{ V}$

# SKM 145 GB 123 D ...

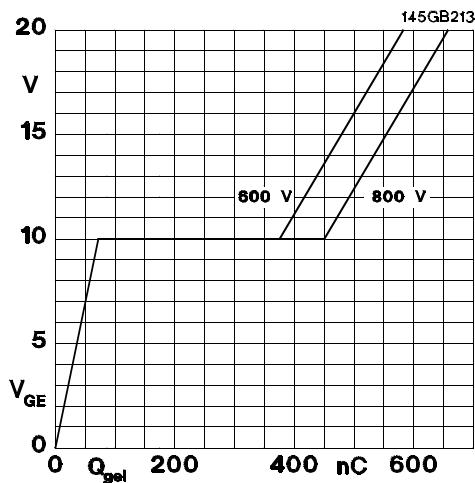


Fig. 13 Typ. gate charge characteristic

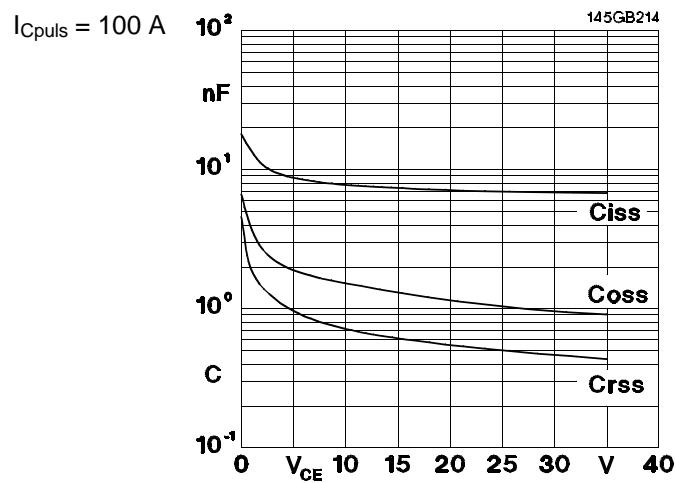


Fig. 14 Typ. capacitances vs.  $V_{CE}$

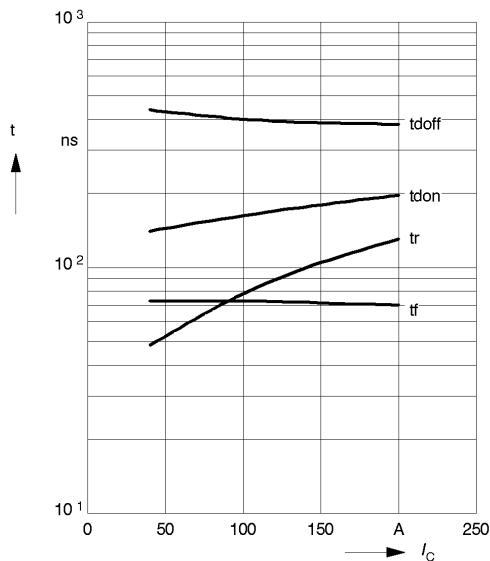


Fig. 15 Typ. switching times vs.  $I_C$

$T_j = 125^\circ\text{C}$   
 $V_{CE} = 600$  V  
 $V_{GE} = \pm 15$  V  
 $R_{Gon} = 6,8 \Omega$   
 $R_{Goff} = 6,8 \Omega$   
induct. load

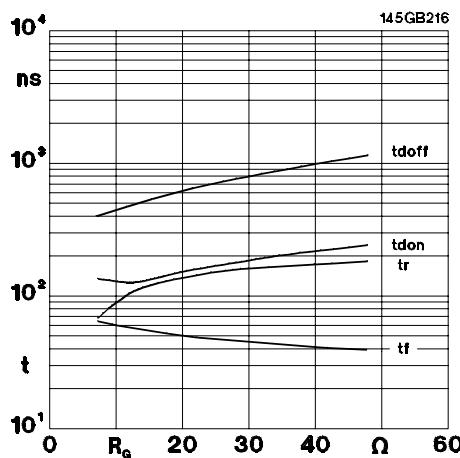


Fig. 16 Typ. switching times vs. gate resistor  $R_G$

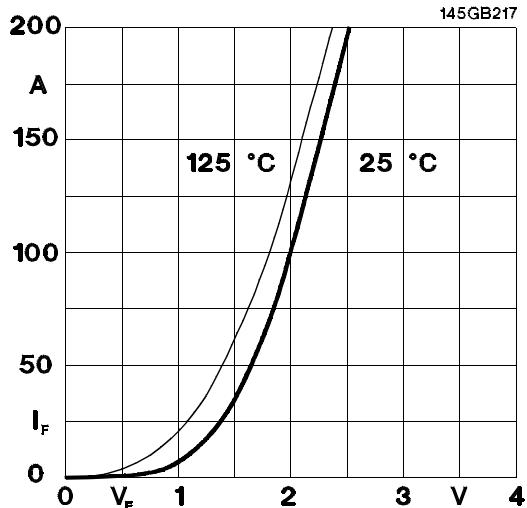


Fig. 17 Typ. CAL diode forward characteristic

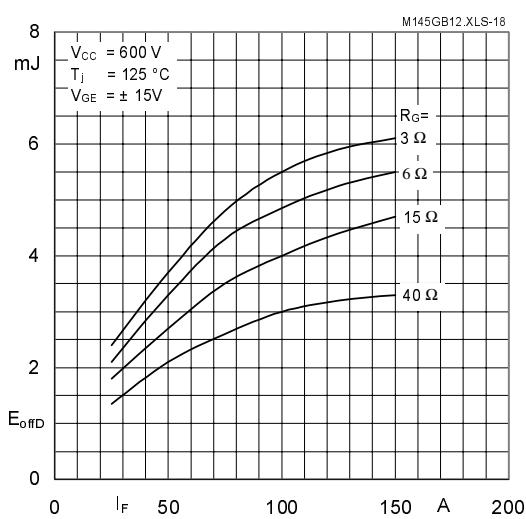


Fig. 18 Diode turn-off energy dissipation per pulse

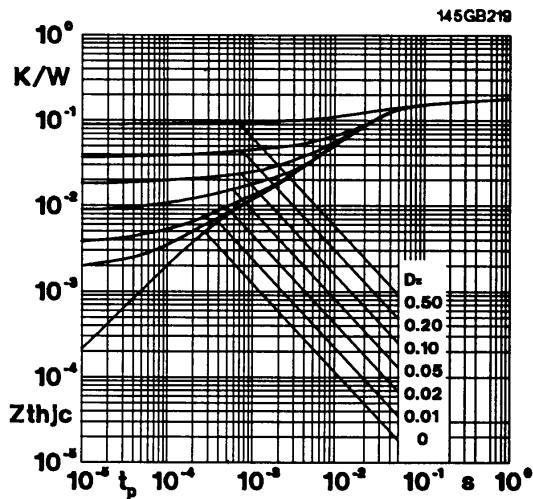


Fig. 19 Transient thermal impedance of IGBT  
 $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

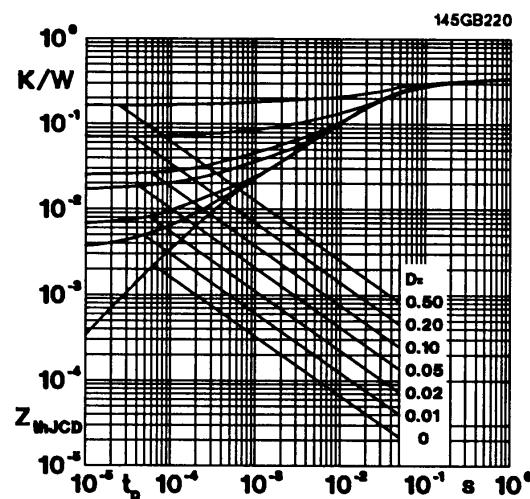


Fig. 20 Transient thermal impedance of  
 inverse CAL diodes  $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

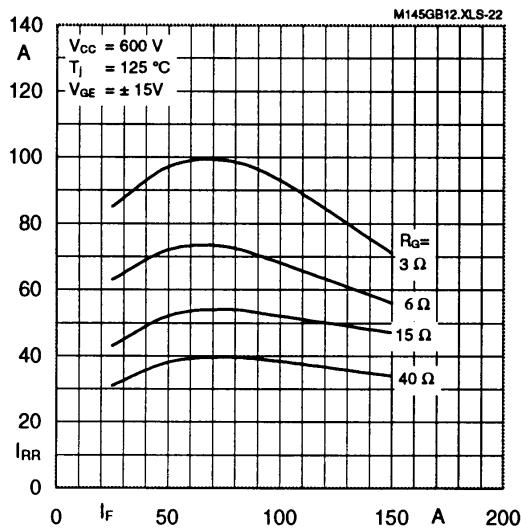


Fig. 22 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(I_F; R_G)$

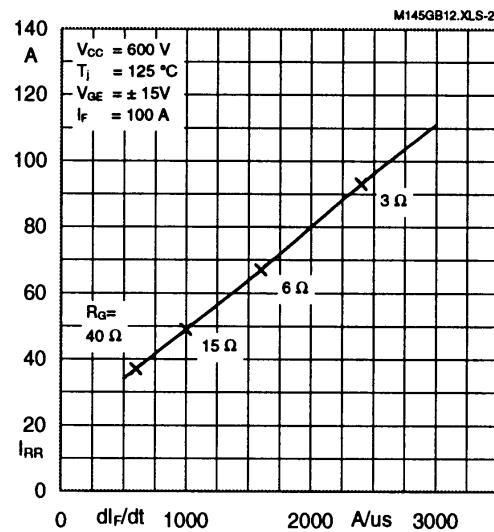


Fig. 23 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(\frac{dI}{dt})$

**Typical Applications**  
**include**  
 Switched mode power supplies  
 DC servo and robot drives  
 Inverters  
 DC choppers (versions GAL and GAR)  
 AC motor speed control  
 Inductive heating  
 UPS Uninterruptable power supplies

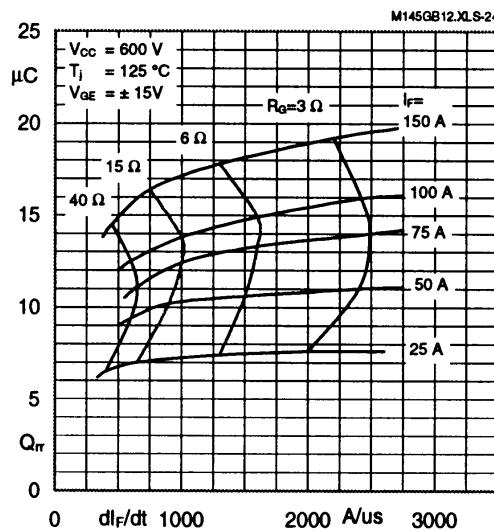


Fig. 24 Typ. CAL diode recovered charge  $Q_{rr} = f(\frac{dI}{dt})$

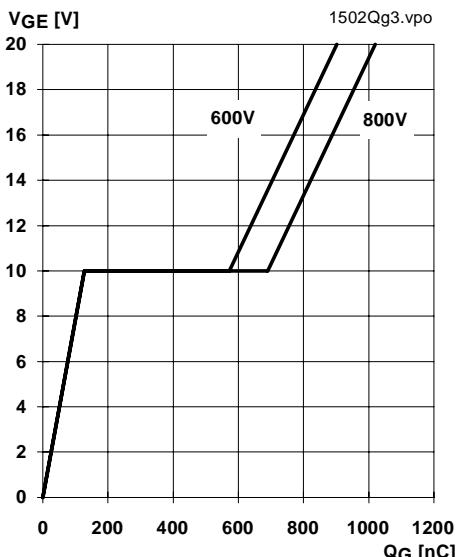


Fig. 13 Typ. gate charge characteristic

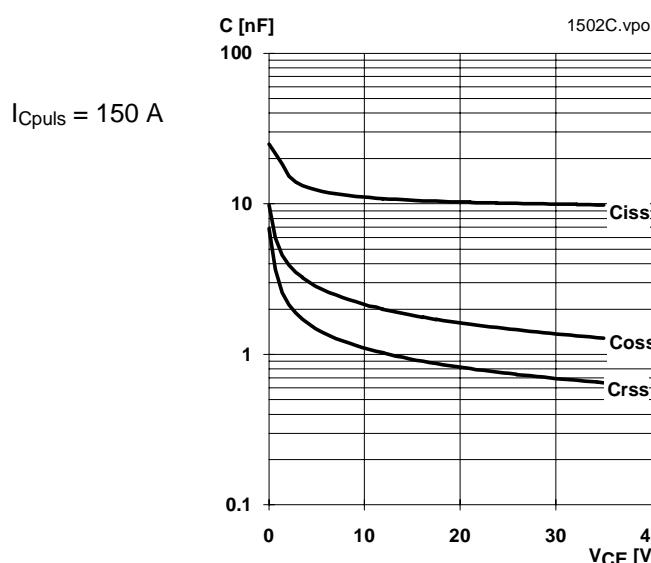


Fig. 14 Typ. capacitances vs.  $V_{CE}$

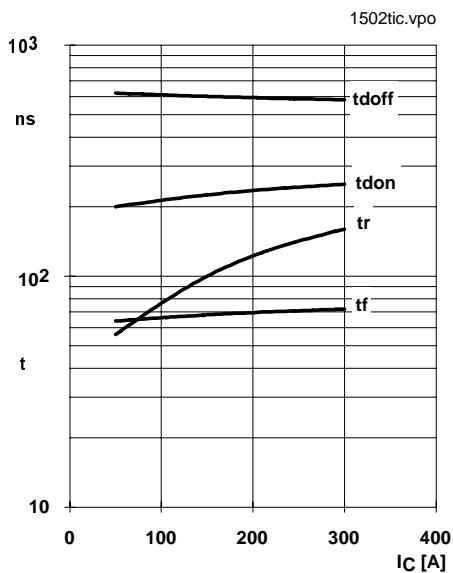


Fig. 15 Typ. switching times vs.  $I_C$

$T_j = 125$  °C  
 $V_{CE} = 600$  V  
 $V_{GE} = \pm 15$  V  
 $R_{Gon} = 5,6$  Ω  
 $R_{Goff} = 5,6$  Ω  
induct. load

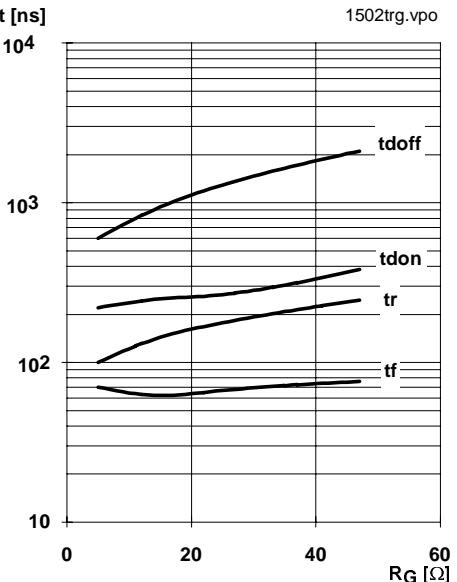


Fig. 16 Typ. switching times vs. gate resistor  $R_G$

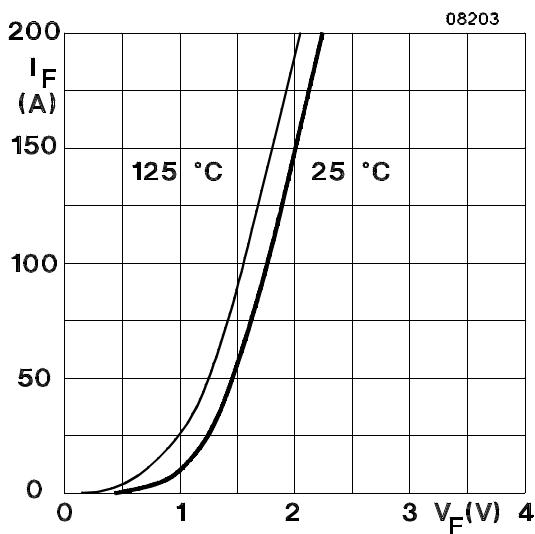


Fig. 17 Typ. CAL diode forward characteristic

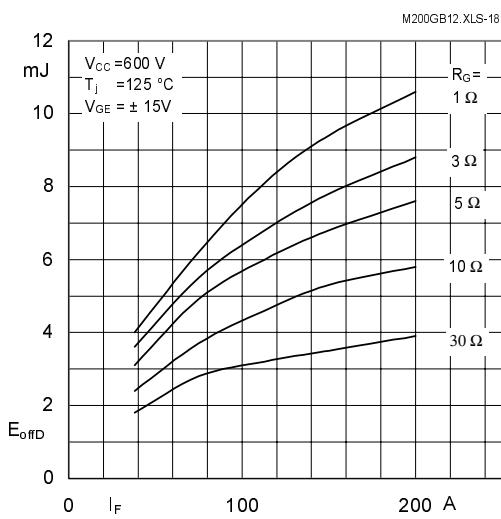


Fig. 18 Diode turn-off energy dissipation per pulse

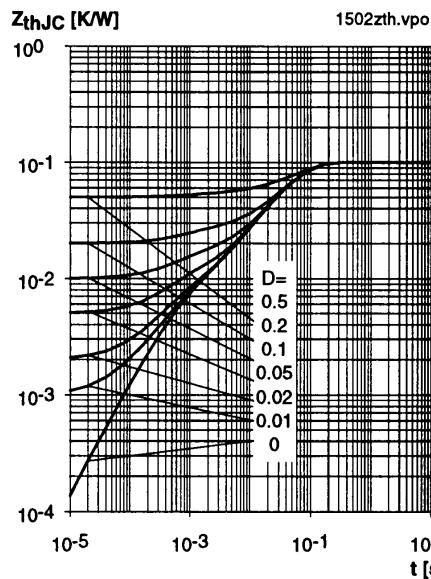


Fig. 19 Transient thermal impedance of IGBT  
 $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

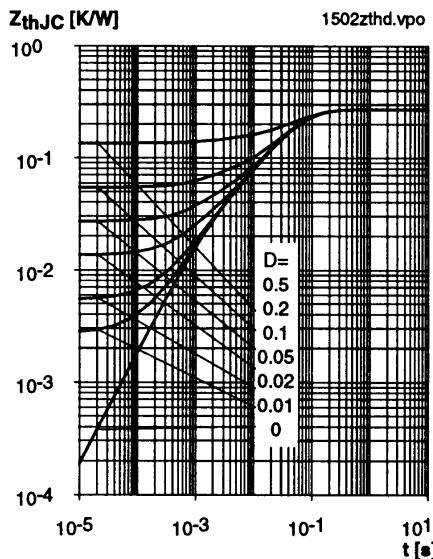


Fig. 20 Transient thermal impedance of inverse CAL diodes  $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

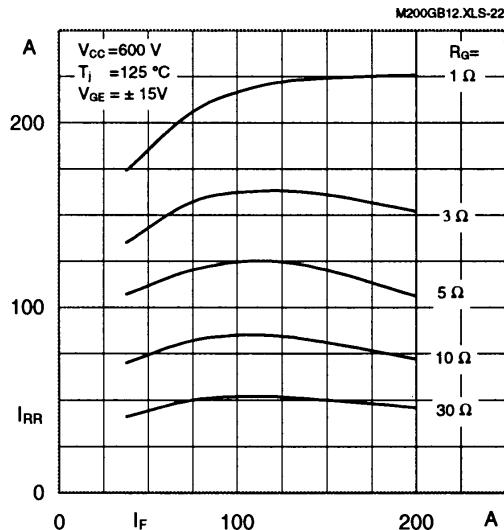


Fig. 22 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(I_F, R_G)$

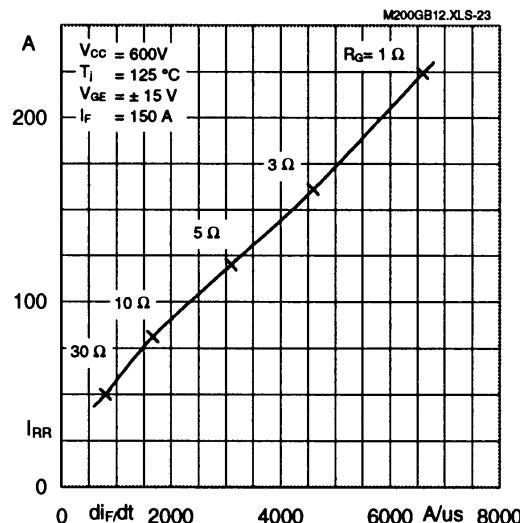


Fig. 23 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(di/dt)$

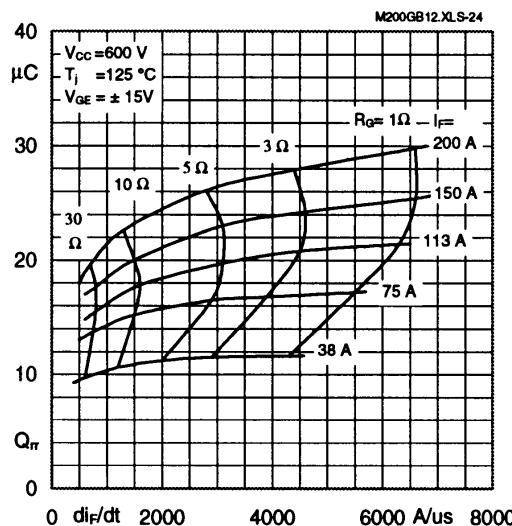


Fig. 24 Typ. CAL diode recovered charge  $Q_{RR}=f(di/dt)$